

2007 69th ARFTG Conference

**Honolulu, Hawaii, USA
8 June 2007**



**IEEE Catalog Number: CFP07ARF-PRT
ISBN: 978-0-7803-9762-0**

TABLE OF CONTENTS

Negative Input Resistance and Real-time Active Load-pull Measurements of a 2.5GHz Oscillator Using a LSNA	1
<i>Inwon Suh, Seok Joo Doo, Patrick Roblin, Xian Cui, Young Gi Kim, Jeffrey Strahler, Marc Vanden Bossche, Roberto Rojas, Hyo Dal Park</i>	
Inter-Laboratory Comparison of CMOS Distortion Measurements	7
<i>Kate A. Remley, Joe Gering, Susan Sweeney, C. Michael Olsen, Cliff Xie, Dave Walker, Tom McKay, Jack Pekarik</i>	
Tuning Range Analysis of Load Pull Measurement Systems and Impedance Transforming Networks	20
<i>Jérôme Sirois, Basim Noori</i>	
True Differential Stimulus Gives Additional Insight into Nonlinear Device Behavior	25
<i>Jochen Simon</i>	
Optimization for Multiport VNA Vector Error Correction	34
<i>David Blackham</i>	
VNA Error Model Conversion for N-Port Calibration Comparison	38
<i>Leonard Hayden</i>	
A Robust Broadband Calibration Method for Wafer-Level Characterization of Multiport Devices	48
<i>Andrej Rumiantsev, Holger Heuermann, Steffen Schott</i>	
Highly Accurate Frequency/Time Domain Characterization of Transmission Lines and Passives for SiP Applications up to 65 GHz	53
<i>Maciej Wojnowski, Mario Engl, Robert Weigel</i>	
A Bilateral Comparison of On-wafer S-parameter Measurements at Millimeter Wavelengths	62
<i>Roland G. Clarke, Jemeela Quraishi, Nick M. Ridler</i>	
Experimental Analysis of On-Wafer De-embedding Techniques for RF Modeling of Advanced RFCMOS and BiCMOS Technologies	69
<i>Jing Wang, Robert Groves, Basanth Jagannathan, Lawrence Wagner</i>	
Design and Analysis of Inductors for 60 GHz Applications in a Digital CMOS Technology	73
<i>Karen Scheir, Piet Wambacq, Yves Rolain, Gerd Vandersteen</i>	
Characterization of Low Dielectric Constant Materials	77
<i>Dietmar Köther, Uwe Gollor</i>	
ANN Modeling of Synthetic Cold Loads	81
<i>Diego Langoni, Mark H. Weatherspoon</i>	
A New Technique for Measuring the Resonant Behavior of Power Amplifier Bias Circuits	89
<i>Scott Rumery, Basim Noori</i>	
A Study of a Variable-Capacitance Drain Network's Influence on Dynamic Behavioral Modeling of an RF Power Amplifier	98
<i>Magnus Isaksson, David Wisell, Anders Eng, Daniel Rönnow</i>	
Hicum and Bsim3v3.2.4 Non Linear Behavior Validation in Rf Bicmos Sigec 0.25µm Process for Bipolar and Cmos Transistors	103
<i>Raphael Paulin, Hélène Beckrich-Ros, Samuel Boret, Patrick Scheer, Didier Céli, Daniel Gloria</i>	
Noncontacting Measurement of Reflection Coefficient and Power in Planar Circuits Up to 40 GHz	107
<i>K. Yhland, J. Stenarson, C. Wingqvist</i>	
Error Propagation from OSL Calibration Standards: Analytical Solution and Experimental Validation	112
<i>Yufeng Han</i>	
Residual Error Models for the SOLT and SOLR VNA Calibration Algorithms	119
<i>J. Stenarson, K. Yhland</i>	
A New Assessment Method for the Residual Errors in SOLT and SOLR Calibrated VNAs	126
<i>J. Stenarson, K. Yhland</i>	
Characterization of MOS Varactor with Large Signal Network Analyser (LSNA) in CMOS 65nm Bulk and SOI Technologies	132
<i>Yvan Morandini, Damien Ducateau, Jean-François Larchanche, Christophe Gaquière, Daniel Gloria</i>	
Optimization of the Substrate Parameters for EM-Simulators	136
<i>F. Korndörfer, F. Sischka</i>	
The Modified Ripple Test for On-Wafer S-Parameter Measurements	142
<i>Holger Heuermann, Andrej Rumiantsev</i>	
An Automated LNA/PPA Characterization System	147
<i>Jean-Francois J. Nowakowski</i>	

Using a Mismatch Transmission Line to Verify Accuracy of a High Performance Noise Figure Measurement System.....	156
<i>Ken Wong, Roger Pollard, Bob Shoulders, Lynn Rhymes</i>	
On-Wafer Time Domain Load-Pull Optimization of Transistor Load Cycle with the New Multi-Harmonic MPT Tuner	161
<i>Fabien De Groote, Olivier Jardel, Jean-Pierre Teyssier, Tony Gasselting, Jan Verspecht, Vince Mallette, Christos Tsironis</i>	
A New Multiline TRL Calibration Technique Implemented with a Variable Phase Shifter.....	167
<i>J. E. Zúñiga-Juárez, J. A. Reynoso-Hernández</i>	
Characterizing the 2.92 mm-Connector Airline Using the Time-domain Gating Methods.....	171
<i>Yeou-Song (Brian) Lee</i>	
45 Degrees Loaded-line Phase Shifter Using Switchable Slow Wave Transmission Lines	176
<i>S. Brebels, X. Rottenberg, P. Ekkels, R. P. Mertens, W. De Raedt</i>	
Dynamic Time-Frequency Waveforms for VSA Characterization of PA Long-term Memory Effects.....	180
<i>Jie Hu, Kevin G. Gard, Nuno Borges Carvalho, Michael B. Steer</i>	
An Innovative Waveguide Interface for Millimeter Wave and Submillimeter Wave Applications.....	185
<i>Yuenie S. Lau, Anthony Denning</i>	
The XML File Format As a General Solution for Measurement Data Storage and Exchange.....	193
<i>Jean-Pierre Teyssier, Fabien De Groote, Markus Mayer, Peter Schlemko, Andrej Rumantsev, Viktor Khutko, Roland Gesche, Ralf Doerner</i>	
Modeling of Multi-Port Inductor Considering Mutual Components	198
<i>Takeshi Ito, Kenichi Okada, Kazuya Masu</i>	
An Automated 1-kHz Null-Balance Receiver for Precision RF and Microwave Attenuation Measurements and Standards	202
<i>Anton Widarta, Hitoshi Iida, Tomoteru Kawakami</i>	
Noise Temperature Measurement Uncertainty Analysis Using Monte Carlo Simulations	205
<i>R. Joe Smith, Mark H. Weatherspoon</i>	
Computing Uncertainties of S-Parameters by Means of Monte Carlo Simulation	212
<i>Johannes Paul Hoffmann, Pascal Leuchtmann, Juerg Schaub, Rudiger Vahldieck</i>	
Determination of Complex Residual Error Parameters of a Calibrated Vector Network Analyzer	219
<i>Gerd Wubbeler, Clemens Elster, Thomas Reichel, Rolf Judaschkez</i>	
LRM: A Quantitative Look at Reference Impedance Contradictions and Other Uncertainty Impacts	223
<i>J. Martens</i>	
Complex Signal Measurement Bench Based on a Special Spectrum Super-Resolution Algorithm.....	230
<i>João Paulo Martins, Paulo J. S. G. Ferreira, Nuno Borges Carvalho</i>	
A General Evaluation Criteria for Behavioral Power Amplifier Modeling.....	235
<i>David Wisell, Magnus Isaksson, Niclas Keskitalo</i>	
Author Index	